

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLN. OF: ANDRE ET AL.

FILED: June 27, 2003

FOR: THIN LAYER OF HAFNIUM OXIDE AND DEPOSIT PROCESS

DOCKET: BREV 13186 DIV

MAIL STOP PATENT APPLICATION

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

The present application is a divisional of U.S. Patent Application Serial No. 09/830,380, filed April 25, 2001. Applicant hereby attaches copies of Form PTO-1449 and Form PTO 892 from the parent application. Copies of the various prior art references listed in the attached Forms PTO-1449 and PTO-892 are not being furnished, since they are available in the parent application. Accordingly, it is respectfully submitted that no copies of these references are believed necessary. The claims in the present application are believed to be patentably distinguished over these references.

This information disclosure statement is being made pursuant to the duty of disclosure imposed by law and formulated in 37 CFR 1.56(A). No representation is made that the information thus disclosed in fact constitutes prior art or that it is the closest prior art, inasmuch as 37 CFR 1.56(A) relies on a materiality concept which depends on subjectivity.

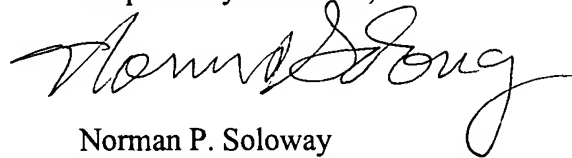
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In the event there are any fee deficiencies or additional fees are payable, please charge them (or credit any overpayment) to our Deposit Account No. 08-1391.

Respectfully submitted,



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**CERTIFICATE OF EXPRESS MAILING**

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I hereby certify that this paper and the papers listed thereon are being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above, and is addressed to: MAIL STOP PATENT APPLICATION, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Signature of person mailing Shauna Bronson  
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**Notice of References Cited**

Application/Control No.

09/830,380

Applicant(s)/Patent Under  
Reexamination  
ANDRE ET AL.

Examiner

Tamra L. Dicus

Art Unit

1774

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
✓	A	US-5,399,435	03-1995	Ando et al.	428/428
✓	B	US-5,623,375	04-1997	Floch et al.	359/871
✓	C	US-5,691,044	11-1997	Oyama et al.	313/461
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

## INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

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Applicant(s)

ANDRE et al

Filing Date

APRIL 25, 2001

Group Art Unit

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		5,670,248	09-23-97	LAZAROV et al	428	304.4	

## FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
		0 486 475 A2	03-03-89	EUROPE	C 03 C	17/23		

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

		"Influence of Microstructure on Laser Damage Threshold of IBS Coatings" by C. J. Stolz et al SPIE Vol. 2714 XP-002111763, pgs. 351-359
		"Thin Films for Optical Systems" edited by F.R. Flory Ecole Nationale Supérieure de Physique de Marseille, Marseille, France Pgs. 521-549

EXAMINER

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\*EXAMINER  
INITIAL

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

"Optical Coatings Deposited by Reactive Ion Plating" by A.J. Waldorf et al  
Applied Optics/October 1, 1993/Vol. 32, No. 28  
pgs. 5583-5593

"Optical Coatings for High-Power Neodymium Lasers" by B. Brauns et al  
Sov. J. Quantum Electron 18 (10) Oct. 1988, c 1989 American Institute of Physics  
pgs. 1286-1290

"Investigation of Optical Damage Mechanisms in Hafnia and Silica Thin Films Using Pairs of Subnanosecond Laser Pulses with Variable Time Delay"  
by L.L. Chase, et al  
J. Appl. Phys. 71 (3) February 1, 1992/American Institute of Physics  
pgs. 1204-1208

"Characterization of Defect Geometries in Multilayer Optical Coatings" by R.J. Tench et al  
J. Vac. Sci. Technol. A 12(5), Sep/Oct 1994  
1994 American Vacuum Society  
pgs. 2808-2813

"Reactive Evaporation of Low-Defect Density Hafnia" by R.Chow et al  
Applied Optics/ October 1, 1993/ Vol. 32, No. 28/ pgs. 5567-5574

"Stress and Environmental Shift Characteristics of HfO<sub>2</sub>/SiO<sub>2</sub> Multilayer Coatings" by J.F. Anzellotti et al  
Proceedings Reprint/SPIE - The International Society for Optical Engineering  
Reprinted from 28th Annual Boulder Damage Symposiumproceedings "Laser-Induced Damage in Optical Materials: 1996"  
October 7-9, 1996, Boulder, Colorado  
SPIE Vol. 2966, pgs. 258-264

"Study of the Structure and Properties of Thick Vacuum Condensates of Nickel, Titanium, Tungsten, Aluminium Oxide and Zirconium Dioxide" by B.A. Movchan et al  
F metal.metalloved., 28, No. 4, 653-660, 1969  
pgs. 83-90

"Nano Absorbing Centers: A Key Point in Laser Damage of Thin Films" by J. Dijon et al  
SPIE Vol. 2966, pgs 315-325

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